Application/Control No. Applicant(s)/Patent Under Reexamination 10/619.608 ABE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Ellen Kim 2874 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,154,592 11-2000 Tagashira, Ryuichi 385/88 Α US-5,127,073 06-1992 Mulholland et al. 385/92 В 03-1956 LEWIS BENJAMIN F; et. al. US-2,737,598 250/214R С 01-2005 D US-6,846,114 Chiu et al. 385/88 * US-4,757,197 07-1988 Lee, Wai-Hon 250/239 Ε 12-2001 US-6,329,607 Fjelstad et al. 174/261 F US-5,781,576 07-1998 Kimura et al. 372/45.01 G US-5,189,363 02-1993 Bregman et al. 324/754 Н US-١ US-DS-Κ US-US-M **FOREIGN PATENT DOCUMENTS** Date Document Number Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.